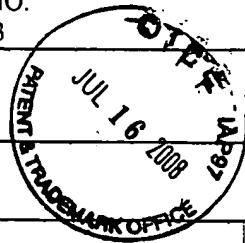


FORM PTO-1449 (Modified)		ATTY. DOCKET NO. P27955	SERIAL NO. 10/538,763
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT: Steven D. SLONAKER et al.	
(Use several sheets if necessary)		FILING DATE: June 10, 2005	GROUP: 2812



REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
						NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

		Nakashima, T., "Impact of Zernike cross-term on linewidth control", SPIE Vol. 4691, 2002, July 15, 2002, pages 33-43
		Shiode, Y., "Method of Zernike coefficients extraction for optics aberration", SPIE Vol. 4691, 2002, pages 1453-1464, Abstract (pages 1453), 2.2 Illumination source Design (pages 1454-1455)
		Nakashima, T., "Evaluation of Zernike sensitivity method for CD distribution", SPIE Vol. 5040, 2003, pages 1600-1610
		Slonaker, S., "Further pursuit of correlation between lens aberration content and imaging performance", SPIE Vol. 4346, 2001, pages 1394-1403
		International Search Report (PCT/ISA/210) for International Application No. PCT/US04/04854

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.